

June 15, 2004

NEWS AND ANNOUNCEMENTS

Harman Music Group Selects Teradyne Transmission X-Ray Product as Sole Test Platform

Harman Music Group, a premium-level manufacturer of audio products, has selected a Teradyne Assembly Test Division test system as their transmission X-ray tester of choice. Harman Music Group has chosen to use the Teradyne XStation HS™ automatic X-ray inspection system exclusively for all manufacturing test in their Sandy, Utah facility. Read more:

http://www.teradyne.com/prods/cbt/news/newsdesk/86news_pr_09062004.html

Teradyne and Acculogic Announce an Agreement on VICTORY™ Software

Acculogic Corporation, a leader in limited access testing including boundary scan (IEEE 1149.1/JTAG) test and in-system programming (ISP), today announced an agreement with Teradyne, Inc. for a source code license to Teradyne's VICTORY boundary scan test generation software. Under the terms of the agreement, Acculogic will obtain VICTORY source code and license to VICTORY intellectual property for the purpose of enhancing its line of boundary-scan test and on-board programming hardware and software. Both Acculogic and Teradyne will market future products derived as a result of this agreement. Read more:

<http://www.acculogic.com/News/news1.htm>

Teradyne Offers Combo 1 and Combo 2 Channel Card Promotion

Due to the overwhelming success of our TestStation trade in program, Teradyne needs to reduce inventory on Combo 1 and Combo 2 cards with ZIF connectors. For a limited time Teradyne is offering deep discounts on these cards. Find out more:

http://www.teradyne.com/prods/cbt/support/supServ_combo.html

New TestStation™ 5.8.0 release

Teradyne is pleased to announce the latest TestStation 5.8.0 software release for GR228X and TestStation customers with an active Software Support Agreement (SSA). 5.8.0 is the latest version of software for ICA-based GR228X and TestStation hardware test platforms. It replaces previous versions of GR228X and Navigate software and provides a powerful environment for developing, debugging, and running in-circuit board test programs. For more information, contact your Teradyne sales engineer, Teradyne Authorized Representative, or Alan Albee, Product Manager, alan.albee@teradyne.com.

TUG 2004 Wrap-Up

The Assembly Test Division hosted a successful Teradyne User Group meeting for customers of its military and aerospace test solutions on May 3-4 in San Jose. Over 60 customers and Teradyners attended two days of sessions devoted to the ATI, BTI, and DTI test instruments, the Spectrum™ 9100 functional test platform, and TestStudio™ and TPS Converter™ software. Papers covered important topics such as re-hosting TPSs and replacing legacy ATE. For more information about TUG 2004 or TUG 2005:

<http://www.teradyne.com/prods/tug/tughome.html>

UPCOMING EVENTS

Guadalajara PCB Test & Inspection Seminar on June 16

On Wednesday, June 16, Teradyne will host a special seminar on the issues and challenges of safely testing low-voltage devices at in-circuit test in Guadalajara, Mexico. The seminar will also feature an overview of Teradyne's D2B™ (Design-to-Build) software and a TestStation LH product demo. This is the second seminar hosted by Teradyne on this topic. Look for future announcements of upcoming seminars starting in mid-August.

Summer Webinar Series on Low-Voltage Test

Mark your calendars and plan to attend one of our special summer webinars on a hot topic: testing low-voltage devices safely at in-circuit test. Do you have low-voltage devices on your PCBs? Do you know they may be vulnerable to over-voltage and over-current conditions during ICT on conventional in-circuit testers? Invest an hour of your time and learn more about this important issue. To see the full schedule or register for a webinar, click here:

<http://www.teradyne.com/prods/cbt/news/tradeshows/webinar30June2004.html>

Autotestcon 2004: Technology & Tradition Unite in San Antonio

Join Teradyne's Assembly Test Division at Autotestcon 2004. San Antonio, Texas will host the 2004 AUTOTESTCON conference from 20-23 September. Over its 35+-year history, this conference has become the premier event for military, government, and commercial industry personnel involved in the development, use, and sustainment of ATE and its related disciplines.

A wide range of real-world applications is addressed in vendor exhibits as well as technical presentations and seminars. Over 200 exhibits displaying the latest advancements in ATE technology will be available for viewing. A strong technical program exploring next-generation concepts and innovative uses of technology has been put together for attendees. Topics scheduled for presentation include: Advances in ATE, TPS Transportability, Integrated Diagnostics, Standardization, Commercial Applications, and many others. To learn more:

<http://www.autotestcon.com/2004/2004.htm>

Teradyne at July Meeting of JTEG

Chuck Pothier will represent Teradyne at the July meeting of the Joint Technology Exchange Group (JTEG) July 13-15 in Crane, Indiana. The July meeting will focus on the "Challenges of Aging ATE Equipment." The Joint Group on Depot Maintenance (JG-DM) chartered the Joint Technology Exchange Group (JTEG) in 1984 to improve coordination in the introduction of new technology, processes, and equipment into DOD depot maintenance activities. The JTEG seeks ways to avoid unnecessary duplication in the area of technology improvement. For more information about JTEG:

<http://www.jdmag.wpafb.af.mil/jteg.htm>